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Science - From Macro- to Nanotomography; 17 -Tomography of Engineering Materials; 18 Diffraction Enhanced Imaging
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Sommario/riassunto

Besides its coverage of the four important aspects of synchrotron sources, materials and material processes, measuring techniques, and applications, this ready reference presents both important method types: diffraction and tomography. Following an introduction, a general section leads on to methods, while further sections are devoted to emerging methods and industrial applications. In this way, the text provides new users of large-scale facilities with easy access to an understanding of both the methods and opportunities offered by different sources and instruments.